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| APPLICATION NO.           | FILING DATE |             | FIRST NAMED INVENTOR | ATTORNEY DOCKET NO. | CONFIRMATION NO |
|---------------------------|-------------|-------------|----------------------|---------------------|-----------------|
| 10/642,607                | (           | 08/19/2003  | Brian A. Vaartstra   | M4065.0133/P133-B   | 2821            |
| 24998                     | 7590        | 01/11/2005  |                      | EXAM                | INER            |
| DICKSTEII<br>2101 L Stree |             | IRO MORIN & | NOVACEK, CHRISTY L   |                     |                 |
| Washington, DC 20037      |             |             |                      | ART UNIT            | PAPER NUMBER    |
|                           |             |             |                      | 2822                |                 |

DATE MAILED: 01/11/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

|  |  | M   |
|--|--|---|
|  | Application No.  | Applicant(s)  |
|  | 10/642,607   | VAARTSTRA ET AL.  |
| Office Action Summary  | Examiner   | Art Unit  |
|  | Christy L. Novacek   | 2822  |
| The MAILING DATE of this communication a<br>Period for Reply   | ppears on the cover sheet wi   | th the correspondence address   |
| A SHORTENED STATUTORY PERIOD FOR REF THE MAILING DATE OF THIS COMMUNICATION  - Extensions of time may be available under the provisions of 37 CFR after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above is less than thirty (30) days, a r  - If NO period for reply is specified above, the maximum statutory perion  - Failure to reply within the set or extended period for reply will, by state Any reply received by the Office later than three months after the mail earned patent term adjustment. See 37 CFR 1.704(b).  | N. 1.136(a). In no event, however, may a re eply within the statutory minimum of thirty od will apply and will expire SIX (6) MON' ute. cause the application to become AB | eply be timely filed  y (30) days will be considered timely.  THS from the mailing date of this communication.  ANDONED (35 U.S.C. & 133) |
| Status   |  |   |
| 1) Responsive to communication(s) filed on 28  | October 2004.  |   |
|  | nis action is non-final.   |   |
| 3) Since this application is in condition for allow  | ance except for formal matte   | ers, prosecution as to the merits is  |
| closed in accordance with the practice under   |  |   |
| Disposition of Claims  |  |   |
| 4) Claim(s) 75-91 is/are pending in the applicat   | ion.   |   |
| 4a) Of the above claim(s) is/are withdr  |  |   |
| 5) Claim(s) is/are allowed.  |  |   |
| 6)⊠ Claim(s) <u>75-91</u> is/are rejected.   |  |   |
| 7) Claim(s) is/are objected to.  |  |   |
| 8) Claim(s) are subject to restriction and   | or election requirement.   |   |
| Application Papers   |  |   |
| 9)☐ The specification is objected to by the Examir   | ner.   |   |
| 10)☐ The drawing(s) filed on is/are: a)☐ ad  | ccepted or b) objected to b  | y the Examiner.   |
| Applicant may not request that any objection to the  |  |   |
| Replacement drawing sheet(s) including the corre   | ection is required if the drawing(   | s) is objected to. See 37 CFR 1.121(d).   |
| 11)☐ The oath or declaration is objected to by the I   | Examiner. Note the attached  | Office Action or form PTO-152.  |
| Priority under 35 U.S.C. § 119   |  |   |
| 12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority document copies of the priority document copies of the certified copies of the priority document copies of the certified copies of the priority document copies of the certified copies of the priority document copies of the certified copies of the priority document copies of the certified copies of the priority document copies of the certified copies of the priority document copies of the certified copies of the priority document copies of the priority do | nts have been received.<br>nts have been received in Apiority documents have been r  | pplication No   |
| * See the attached detailed Office action for a lis  |  | eceived.  |
| Attachment(s)  | Pro  |   |
| ) Notice of References Cited (PTO-892)  Notice of Draftsperson's Patent Drawing Review (PTO-948)   |  | ummary (PTO-413)<br>/Mail Date  |
| Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08 Paper No(s)/Mail Date   |  | formal Patent Application (PTO-152)   |

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#### **DETAILED ACTION**

This office action is in response to the amendment filed October 28, 2004.

## Response to Amendment

The amendment of claim 91 is sufficient to overcome the rejection of claim 91 under 35 U.S.C. 112, second paragraph stated in the previous office action. Therefore, this rejection is withdrawn.

# Response to Declaration

The declaration filed on October 28, 2004 under 37 CFR 1.131 is sufficient to overcome the Russell (US 6,235,631), Iyer (6,156,630) and Murzin (US 6,117,772) references. The declaration does not overcome the Ovshinsky (US 6,087,674) and Sandhu (US 6,313,035) references. The declaration does not overcome the Sandhu reference because the effective filing date of the reference is prior to June 30, 1997. The declaration does not overcome the Ovshinsky reference because the portions of the reference that recite the limitations in Applicants' claims are given the benefit of its parent patent's effective filing date.

#### Claim Objections

Claim 89 is objected to because of the following informalities: As stated in the previous office action, lines 9-11 of claim 89 recite the limitation of "said chamber". There is insufficient antecedent basis for this limitation in the claim. Appropriate correction is required.

### Claim Rejections - 35 USC § 112

The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

Claim 81 is rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention. Claim 81 recites the limitation of "said titanium precursor". This claim lacks antecedent basis. Claim 75, upon which claim 81 now depends, does not recite the limitation of a titanium precursor.

# Claim Rejections - 35 USC § 103

The text of those sections of Title 35, U.S. Code not included in this action can be found in a prior Office action.

Claims 75-85 and 88-91 are rejected under 35 U.S.C. 103(a) as being unpatentable over Ovshinsky et al. (US 6,087,674, previously cited) in view of Lu (US 6,017,818) and Mosely et al. (US 5,877,087).

Regarding claims 75 and 88, Ovshinsky discloses depositing a single layer (6,8) containing a first metal (titanium), aluminum, nitrogen and boron on a semiconductor substrate (10) (col. 9, ln. 44 – col. 10, ln. 5 of 6,087,674 patent and column 10, ln 33-61 of the parent 5,825,046 patent). Ovshinsky does not disclose what method is used to deposit this layer. Like Ovshinsky, Lu discloses depositing a single layer containing titanium, boron and nitrogen as part of a semiconductor device manufacturing process (Abstract). Lu teaches that this layer is deposited using a particular chemical vapor deposition (CVD) process because it offers the advantages of being able to deposit a layer having good conformability and low defect density (col. 2, ln. 29-48). Lu's CVD method involves placing the wafer into a CVD chamber, heating the wafer and introducing a metal (titanium) precursor, a nitrogen precursor and a boron

precursor into the chamber to simultaneously deposit the Ti-B-N layer (col. 3, ln. 30-55). Lu does not disclose incorporating aluminum into the layer. Like the Ti-B-N layer of Lu, Mosely discloses that an aluminum-containing layer can also be conformally deposited by a CVD process using an aluminum precursor (col. 5, ln. 8-22). At the time of the invention, it would have been obvious to one of ordinary skill in the art to deposit the Ti-Al-N-B layer of Ovshinsky using a CVD process as disclosed by Lu and Mosely because these reference teach that CVD will result in a layer that is conformal and of a low defect density.

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Regarding claim 76, Lu discloses that a single gas serves as the titanium precursor and the nitrogen precursor (Abstract).

Regarding claims 77, 79 and 91, Lu discloses that the titanium and nitrogen precursor can be Ti(N(CH<sub>3</sub>)<sub>2</sub>)<sub>4</sub> (tetrakis-dimethyl-amido-titanium) (TDMAT) (Abstract).

Regarding claim 78, Lu discloses heating the wafer to a temperature of 300-500°C (col. 3, ln. 47-50).

Regarding claims 80 and 90, Mosely discloses that the aluminum precursor is dimethylaluminumhydride (DMAH) (col. 5, ln. 8-22).

Regarding claim 81, Lu discloses that the titanium precursor can be tetrakisdiethylamidotitanium (TDEAT) (col. 6, ln. 51-58).

Regarding claim 82, Lu discloses that the metal (titanium) precursor is an organometallic compound.

Regarding claim 83, Lu discloses that the boron precursor is a boron reactant gas (col. 6, ln. 51-58).

Regarding claims 84 and 85, Lu discloses that a nitrogen precursor is a nitrogen reactant gas.

Regarding claim 89, for the reasons discussed above in reference to claim 75, it would have been obvious to one of ordinary skill in the art to deposit the Ti-Al-N-B layer of Ovshinsky using a CVD process as disclosed by Lu and Mosely. Lu and Mosely disclose that the CVD process may be conducted by heating the wafer within the range of 250-500 degrees Celsius (col. 3, ln. 49-51 of Lu and col. 5, ln. 13-14 of Mosely). Lu and Mosely disclose that the pressure within the reactor may be 0.1-80 torr (col. 3, ln. 51 of Lu and col. 5, ln. 16-18 of Mosely).

Claim 86 is rejected under 35 U.S.C. 103(a) as being unpatentable over Ovshinsky et al. (US 6,087,674) in view of Lu (US 6,017,818) and Mosely et al. (US 5,877,087) as applied to claim 75 above, and further in view of Sandhu et al. (US 6,313,035, previously cited).

Regarding claim 86, Ovshinsky, Lu and Mosel do not disclose the structure of the CVD apparatus used to deposit the Ti-Al-B-N layer. Sandhu discloses using a CVD process to deposit a titanium-containing layer from a TDMAT precursor. Sandhu states that in order to form a titanium-containing layer having good film uniformity, a carrier gas is used to vaporize and transport the TDMAT precursor in a bubbler (col. 6, ln. 42-62). At the time of the invention, it would have been obvious to one of ordinary skill in the art to use a bubbler to provide the titanium precursor because Russell discloses using a TDMAT precursor to CVD deposit the titanium-containing layer and Sandhu states that by providing a carrier gas with the TDMAT in a bubbler, a titanium-containing film having good uniformity can be formed.

Claim 87 is rejected under 35 U.S.C. 103(a) as being unpatentable over Ovshinsky et al. (US 6,087,674) in view of Lu (US 6,017,818) and Mosely et al. (US 5,877,087) as applied to claim 75 above, and further in view of Ward et al. ("New Developments in CVD Source Delivery and Source Reagents").

Regarding claim 87, Ovshinsky, Lu and Mosely do not disclose the structure of the CVD apparatus used to deposit the Ti-Al-B-N layer. Ward discloses it is beneficial to use a using liquid source delivery CVD process to deposit a titanium-containing layer from a TMDAT precursor because vapor source delivery CVD methods suffer the problems of being difficult to control and maintain. Ward teaches that direct liquid injection of precursors in a chemical vapor deposition process eliminates those problems. At the time of the invention, it would have been obvious to one of ordinary skill in the art to use a direct liquid injection system to provide the precursors because Lu and Mosely disclose using CVD to deposit the Ti-Al-N-B layer and Ward teaches that by providing the precursors to the CVD chamber by way of a direct liquid injection system, the problems associated with a vapor source delivery system can be avoided.

## Response to Arguments

Applicant's arguments filed October 28, 2004 have been fully considered but they are not persuasive.

Regarding the declaration filed on October 28, 2004, Applicant states, "The subject matter of Ovshinsky relied on by the Office Action has an effective filing date of April 20, 1998. Ovshinsky is a continuation-in-part of U.S. Application No. 098/739,080 to Czubatyj et al. (now U.S. Patent No. 5,825,046), having a filing date of October 28, 1996, but the subject matter relied on by the Office Action, specifically, a "thin film layer includling one or more elements

selected from the group consisting of Ti, V, Cr, Zr, Nb, Mo, Hf, Ta, W and mixtures or alloys thereof in combination with two or more elements selected from the group consisting of B, C, N, 0, Al, Si, P, S and mixtures and alloys thereof" (Ovshinsky, Col 9, line 66-Co1. 10, line 4), does not appear anywhere in the parent application." This is untrue. Column 10, lines 35-40 of the Czubatyj parent patent states, "the adjacent thin-film layer 38, 34 may be formed from a compound which includes one element selected from the group consisting of Ti, V, Cr, Zr, Nb, M [sic], Hf, Ta, W, and one or more elements selected from the group consisting of B, C, N, Al, Si, P, S." Therefore, the 6,087,674 patent receives the benefit of its parent patent's filing date for these claim limitations.

Applicant's arguments regarding the rejections of claims 75-91 using the Russell, Iyer and Muzhin patents are moot in view of the new grounds of rejection necessitated by the declaration filed on October 28, 2004.

#### Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Christy L. Novacek whose telephone number is (571) 272-1839. The examiner can normally be reached on Monday-Thursday and alternate Fridays 7:30 - 5:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Amir Zarabian can be reached on (571) 272-1852. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

CLN January 3, 2004

Michael Trinh Primary Examiner Page 8